



MC33664

Isolated network high-speed transceiver

Rev. 1.0 — 23 May 2018

Short data sheet: technical data

1 General description

The MC33664 is a SMARTMOS transceiver physical layer transformer driver designed to interface a microcontroller conveniently to a high speed isolated communication network. MCU serial peripheral interface (SPI) data bits are directly converted to pulse bit information and transferred to the bus network.

Slave response messages use the same structure to send pulse bit information to the MC33664, which is converted and sent back to the MCU as a SPI bit stream.

2 Features and benefits

- 2.0 Mbit/s isolated network communication rate
- Dual SPI architecture for message confirmation
- Robust conducted and radiated immunity with wake-up
- 3.3 V and 5.0 V compatible logic thresholds
- Low sleep mode current with automatic bus wake-up
- Ultra-low radiated emissions

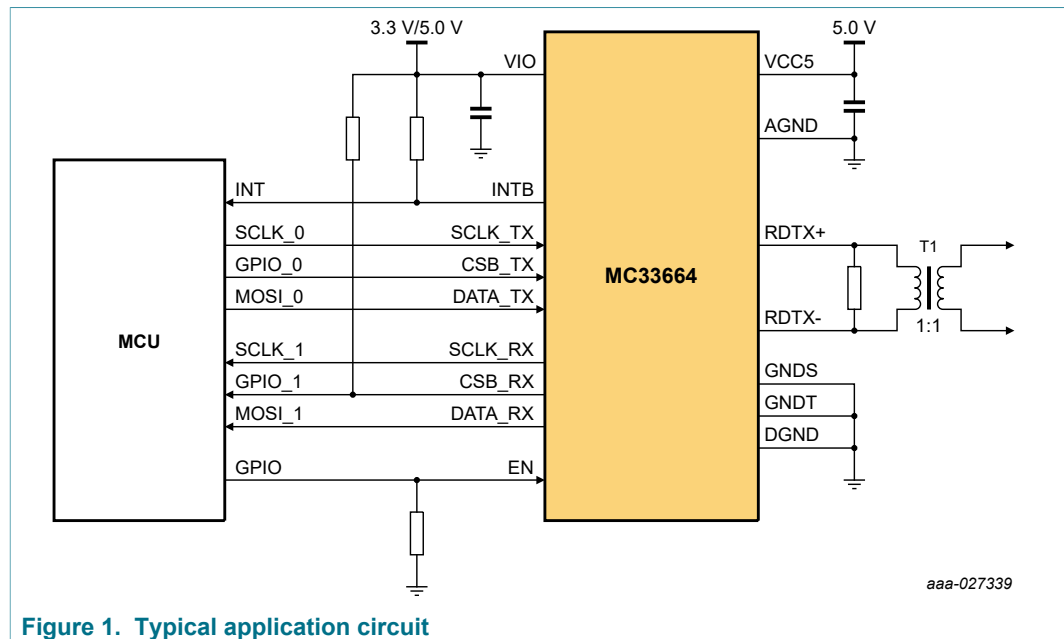


Figure 1. Typical application circuit

3 Applications

- Automotive communication network
- Industrial communication network
- Utility vehicle battery systems
- Forklift/mining battery systems
- Battery backup systems

4 Ordering information

Table 1. Ordering information

Type number	Package			Version
	Name	Description	T _{amb} [°C]	
MC33664ATL1EG ^[1]	SO16	plastic small outline package; 16 leads; 1.27 mm pitch; body 9.9 mm × 3.9 mm × 1.75 mm	-40 to +125	SOT109-5

[1] To order parts in tape and reel, add R2 suffix to the part number.

5 Pinning information

5.1 Pinning

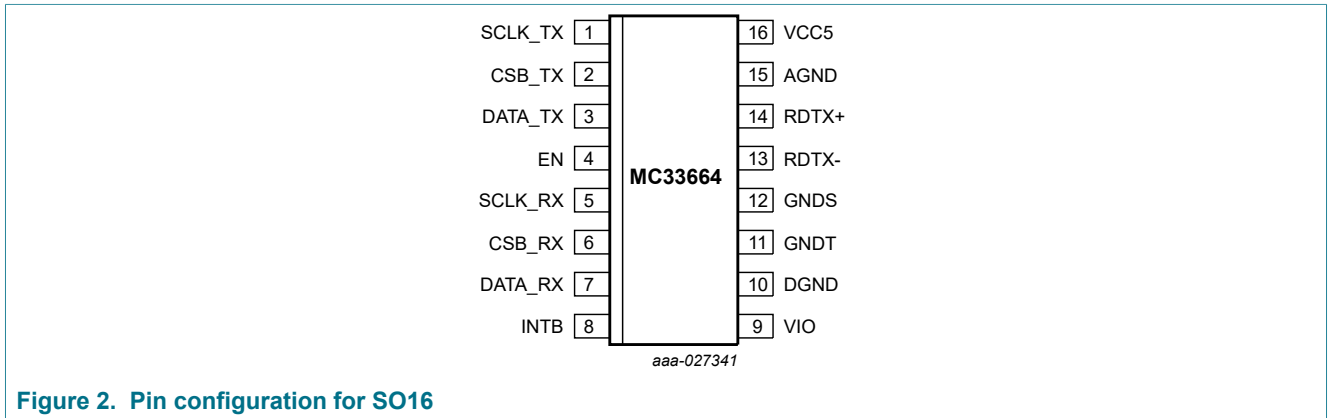


Figure 2. Pin configuration for SO16

5.2 Pin description

Table 2. Pin description

Symbol	Pin	Type	Description
SCLK_TX	1	input	SPI transmit clock from the microcontroller to the MC33664
CSB_TX	2	input	SPI transmit chip select from the microcontroller to the MC33664
DATA_TX	3	input	SPI transmit data from the microcontroller to the MC33664
EN	4	input	enable control pin for the MCU to control the MC33664 to Sleep mode or Normal mode
SCLK_RX	5	output	message receive SPI clock output to the microcontroller
CSB_RX	6	output	message receive SPI chip select output to the microcontroller
DATA_RX	7	output	message receive SPI data output to the microcontroller
INTB	8	output	digital interrupt pin used to trigger MCU wake-ups
VIO	9	power	digital 3.3 V/5.0 V power to the IC
DGND	10	ground	digital ground
GNDD	11	ground	terminate to ground
GNDS	12	ground	substrate ground; terminate to ground
RDTX-	13	I/O	transformer communication bi-directional bus
RDTX+	14	I/O	transformer communication bi-directional bus
AGND	15	ground	analog ground
VCC5	16	input	5.0 V input supply

6 Ratings and operating requirements relationship

The operating voltage range pertains to the VCC5 and VIO pins referenced to the AGND and DGND pins.

Table 3. Ratings versus operating requirements

Fatal range	Lower limited operating range	Normal operating range	Upper limited operating range	Fatal range
$V_{PWR} < -0.3\text{ V}$ Permanent failure may occur	$4.5\text{ V} \leq V_{CC5} \leq 4.75\text{ V}$ no permanent failure, but IC functionality is not guaranteed	$4.75\text{ V} \leq V_{CC5} \leq 5.5\text{ V}$ $3.1\text{ V} \leq V_{IO} \leq 5.5\text{ V}$ 100 % functional	$5.5\text{ V} \leq V_{CC5} \leq 7.0\text{ V}$ $5.5\text{ V} \leq V_{IO} \leq 7.0\text{ V}$	$7.0\text{ V} \leq V_{CC5}$ $7.0\text{ V} \leq V_{IO}$ permanent failure may occur
	$0\text{ V} \leq V_{CC5} \leq 4.5\text{ V}$ $0\text{ V} \leq V_{IO} \leq 3.1\text{ V}$ reset			
handling range; no permanent failure				

7 Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

All voltages are respect to reference ground (AGND and DGND) unless otherwise noted. Exceeding these ratings may cause malfunction or permanent damage to the device.

Symbol	Parameter	Conditions	Min	Max	Unit
V _{IO}	supply input voltage		-0.3	+7.0	V
V _{CC5}	supply input voltage		-0.3	+7.0	V
EN	digital enable pin for Sleep or Normal mode		-0.3	V _{IO} + 0.3	V
RDTX+, RDTX-	communication bus		-10	+10	V
INTB	interrupt pin		-0.3	V _{IO} + 0.3	V
SCLK_TX, SCLK_RX, CSB_TX, CSB_RX, DATA_TX, DATA_RX	serial peripheral interface communication ports		-0.3	V _{IO} + 0.3	V
V _{ESD}	electrostatic discharge voltage	human body model (HBM) ^[1]	±2000	-	V
		charge device model (CDM)	±500	-	V
		CDM corner pins	±750	-	V
		machine model (MM)	±200	-	V
		RDTX+, RDTX-; HBM	±4000	-	V
		RDTX+, RDTX-; MM	±200	-	V

[1] Electrostatic discharge (ESD) testing is performed in accordance with the HBM (C_{ZAP} = 100 pF, R_{ZAP} = 1500 Ω).

8 Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
T_{amb}	ambient temperature		-40	+125	°C
T_j	junction temperature		[1] -40	+150	°C
T_{stg}	storage temperature		-55	+150	°C
$T_{reflow(peak)}$	peak reflow temperature		[2] [3] -	260	°C
$R_{th(j-a)}$	thermal resistance from junction to ambient	single layer (1s)	[4] -	125	°C/W
$R_{th(j-pcb)}$	thermal resistance from junction to printed-circuit board	multi layer (2s2p)	[5] -	62	°C/W

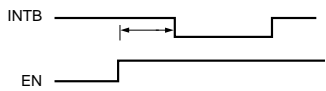
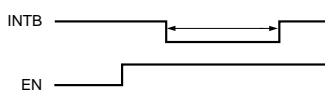
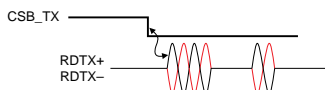
- [1] Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
- [2] Pin soldering temperature limit is for 10 seconds maximum duration. Not designed for immersion soldering. Exceeding these limits may cause malfunction or permanent damage to the device.
- [3] Package reflow capability meets Pb-free requirements for JEDEC standard J-STD-020C. For peak package reflow temperature and moisture sensitivity levels (MSL), go to <http://www.nxp.com>, search by part number [e.g. remove prefixes/suffixes and enter the core ID to view all orderable parts (i.e. MC33xxxD enter 33xxx)], and review parametric.
- [4] Per SEMI G38-87 and JEDEC standard JESD51-2 with the single-layer board horizontal.
- [5] Indicates the maximum thermal resistance between the die and the exposed pad surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

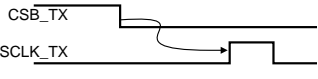
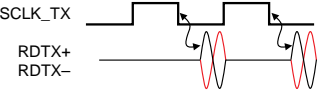
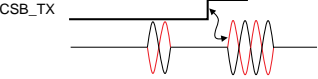
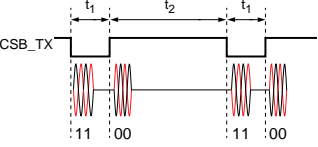
9 Characteristics

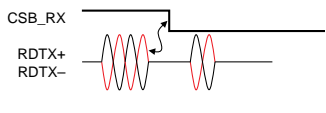
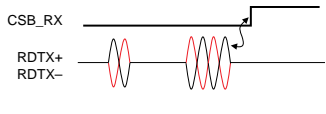
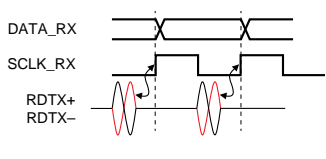
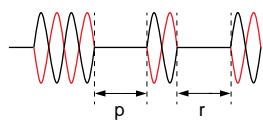
Table 6. Characteristics

Characteristic noted under conditions $4.75\text{ V} \leq V_{CC5} \leq 5.5\text{ V}$, $3.1\text{ V} \leq V_{IO} \leq 5.5\text{ V}$, $-40\text{ °C} \leq T_{amb} \leq 125\text{ °C}$, unless otherwise noted. Typical values noted reflect the approximate parameter mean at $V_{CC5} = 5.0\text{ V}$, $V_{IO} = 3.3\text{ V}/5.0\text{ V}$, $T_{amb} = 25\text{ °C}$ and device operating under nominal conditions unless otherwise noted.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Power supply VCC5						
V_{CC5}	supply voltage	fully operational	4.75	—	5.5	V
		limited operation	4.5	—	4.75	V
$I_{VCC5(NORMAL)}$	supply current	Normal mode; EN = 1; continuous transmit; 50 Ω load		40		mA
		Normal mode; EN = 1; continuous receive		3.0		mA
$I_{VCC5(SLEEP)}$	supply current	Sleep mode; EN = 0; INTB = 5.0 V		30		μ A
V_{CC5UV}	VCC5 undervoltage POR threshold		4.0	—	4.5	V
V_{CC5UV_FLT}	VCC5 undervoltage POR filter			2.5		μ s
$V_{CC5UVHYS}$	VCC5 undervoltage POR hysteresis			100		mV
Power supply VIO						
V_{IO}	supply voltage		3.1	—	5.5	V
V_{IOUV}	VIO undervoltage POR threshold		2.2	—	3.1	V

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{IO_UV_FLT}	VIO undervoltage POR filter			2.5		μs
V _{IO_UV_HYS}	VIO undervoltage POR hysteresis			100		mV
I _{VIO(SLEEP)}	VIO sleep current	EN = 0; INTB = 1	0.1	—	4.5	μA
I _{VIO(NORMAL)}	VIO Normal mode current	EN = 1; continuous communication; SPI_1 open		1.0		mA
Logic transmit EN, CSB_TX, SCLK_TX, DATA_TX						
V _{IH}	HIGH-level input voltage		1.7	—	V _{IO} + 0.3	V
V _{IL}	LOW-level input voltage		—	—	0.95	V
V _{hys}	hysteresis voltage			150		mV
R _{pd}	pull-down resistance	EN, SCLK_TX, DATA_TX		100		kΩ
R _{pu}	pull-up resistance	CSB_TX		100		kΩ
t _{READY}	Sleep mode to Normal mode	EN LOW to HIGH transition to device ready to transmit	—	—	100	μs
t _{INTB_PULSE_DELAY}	EN LOW to HIGH transition to INTB verification pulse		—	—	100	μs
						
t _{INTB_PULSE}	INTB verification pulse duration		—	100	—	μs
						
f _{SCLK_TX}	SPI_0 frequency	SCLK_TX		2.0		MHz
a	SCLK_TX HIGH	see Figure 3		250		ns
b	SCLK_TX LOW	see Figure 3		250		ns
e	SCLK_TX to CSB_TX	see Figure 3	—	250	—	ns
L	CSB_TX to start of message		—	—	1.1	μs
						

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f	falling edge of CSB_TX to rising edge SCLK_TX 	see Figure 3	1.75	—	—	µs
t _{RDTX_DLY}	propagation delay 	SCLK_TX LOW to sine out ^[1]	—	80	150	ns
g	SCLK_TX LOW to CSB_TX HIGH	see Figure 3	600	—	—	ns
c	DATA_TX to SCLK_TX setup	see Figure 3	40	—	—	ns
d	DATA_TX hold	see Figure 3	40	—	—	ns
t _{CSB_TX_HIGH_EOM}	propagation delay 	CSB_TX LOW to HIGH ^[1] to end of message	—	—	150	ns
t ₁	CSB_TX wake#up pulse sequence timing 	CSB_TX LOW period		21		µs
t ₂		CSB_TX HIGH period		600		µs
h	time between consecutive transmit messages	see Figure 3	1.0	3.0	—	µs
Logic receive pins (CSB_RX, SCLK_RX, DATA_RX)						
V _{OH}	HIGH-level output voltage	I _{OH} = -2.0 mA; V _{IO} = 3.1 V	V _{IO} - 0.4	—	—	V
V _{OL}	LOW-level output voltage	I _{OL} = -2.0 mA; V _{IO} = 3.1 V	—	—	0.4	V
f _{SPI}	SPI_1 frequency	SCLK_RX		2.0		MHz
q	pulse frequency	see Figure 4		4.0		MHz
o	start of message	see Figure 4 ^[1]		500		ns
a	SCLK_RX HIGH			250		ns
b	SCLK_RX LOW			250		ns

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
$t_{SOM_CSB_RX}$	start of message to CSB_RX 	[1]		160		ns	
$t_{EOM_CSB_RX}$	end of message to CSB_RX 	[1]		60		ns	
$t_{PDB_SCLK_DATA_RX}$	pulse data bit to DATA_RX and SCLK_RX 	[1]		280		ns	
r	start of message to MSB (receive) 	see Figure 4	[1]	—	250	—	ns
p		see Figure 4	[1]	—	600	—	ns
m	time between consecutive messages received	see Figure 4	1.0	3.0	—	μ s	
Bus differential transmitter/receiver							
$V_{RDTX(PK_DIFF)}$	RDTX \pm differential output voltage	$R_L = 50 \Omega$; $V_{CC5} = 4.75 \text{ V}$		2.5		V	
I_{RDTX}	RDTX \pm current limit	sinking/sourcing to 2.5 V	65	—	300	mA	
$V_{RDTX_IN(TH)}$	RDTX \pm differential receiver threshold voltage	rising edge		0.74		V	
		falling edge		0.61	0.70	V	
$V_{RDTX_IN_HYST}$	RDTX \pm differential receiver threshold voltage hysteresis			130		mV	
V_{RDTX_BIAS}	transformer bias voltage	transmitter in 3-state		2.5		V	
f_{RDTX}	transmit/receive pulse frequency			4.0		MHz	
Wake-up receiver							
V_{RDTXWU_TH}	RDTX \pm wake#up differential receiver threshold voltage	rising edge		0.6		V	
		falling edge		0.6		V	
$V_{RDTXWU_TH_HYS}$	RDTX \pm wake#up differential receiver threshold hysteresis			100		mV	

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{RDTXWU_FLT}	RDTX± wake#up filter			50		ns

[1] All bus network signals to SPI timing are referenced to 0.8 V differential threshold.

9.1 Timing diagrams

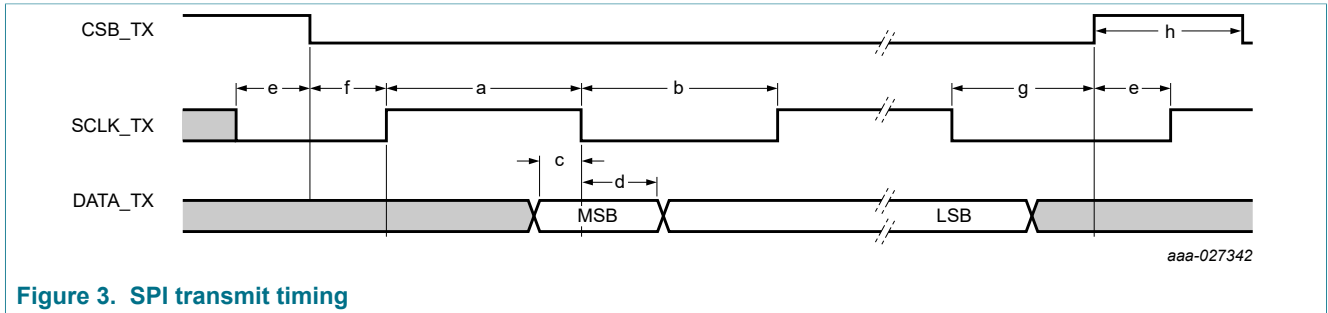


Figure 3. SPI transmit timing

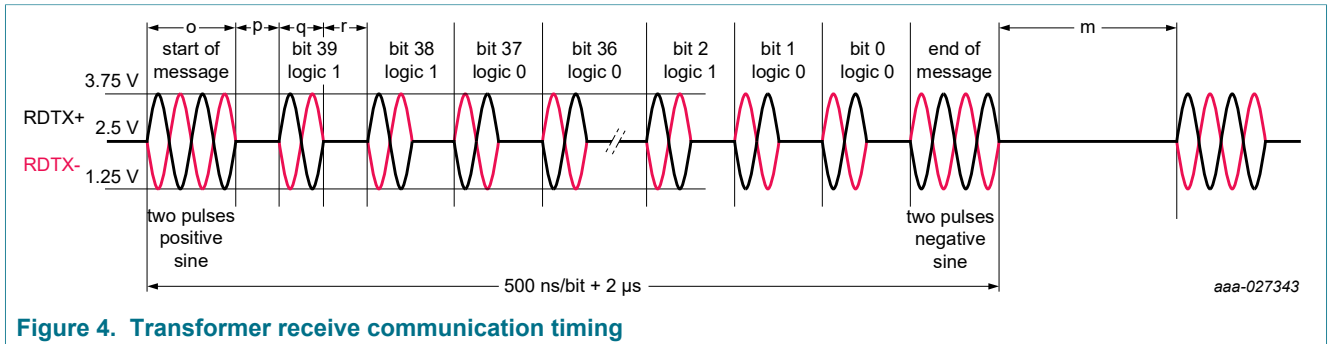


Figure 4. Transformer receive communication timing

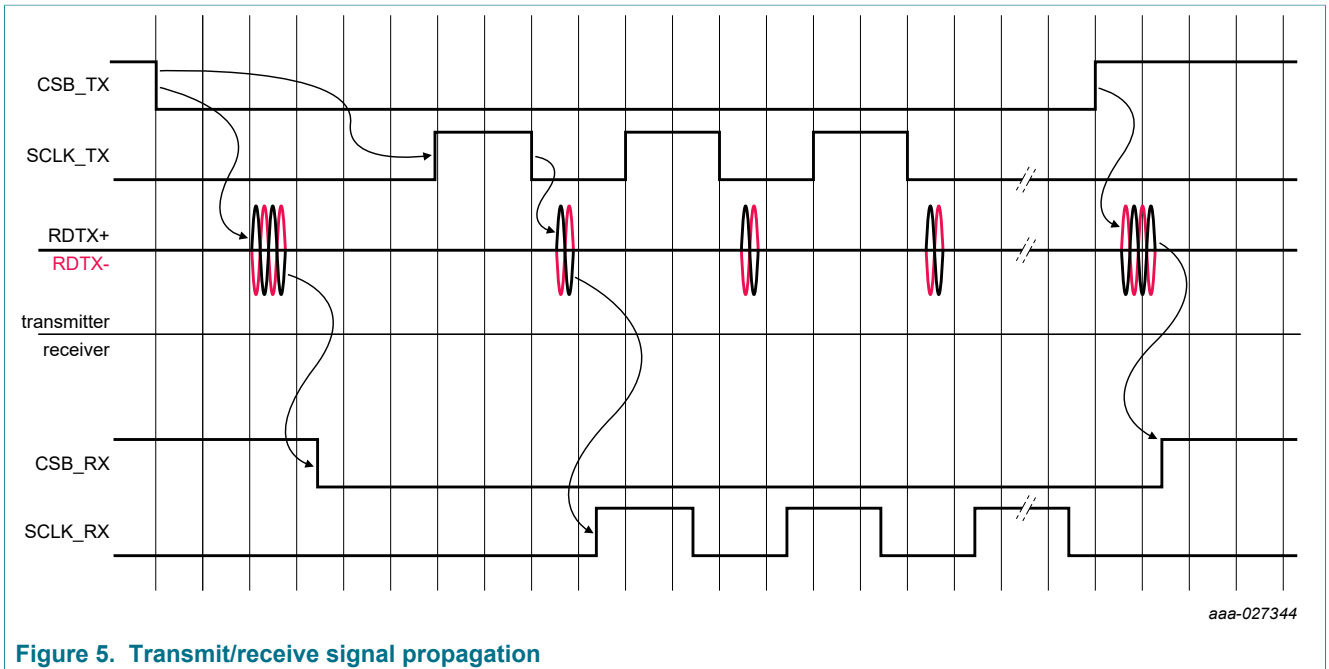


Figure 5. Transmit/receive signal propagation

10 Package outline

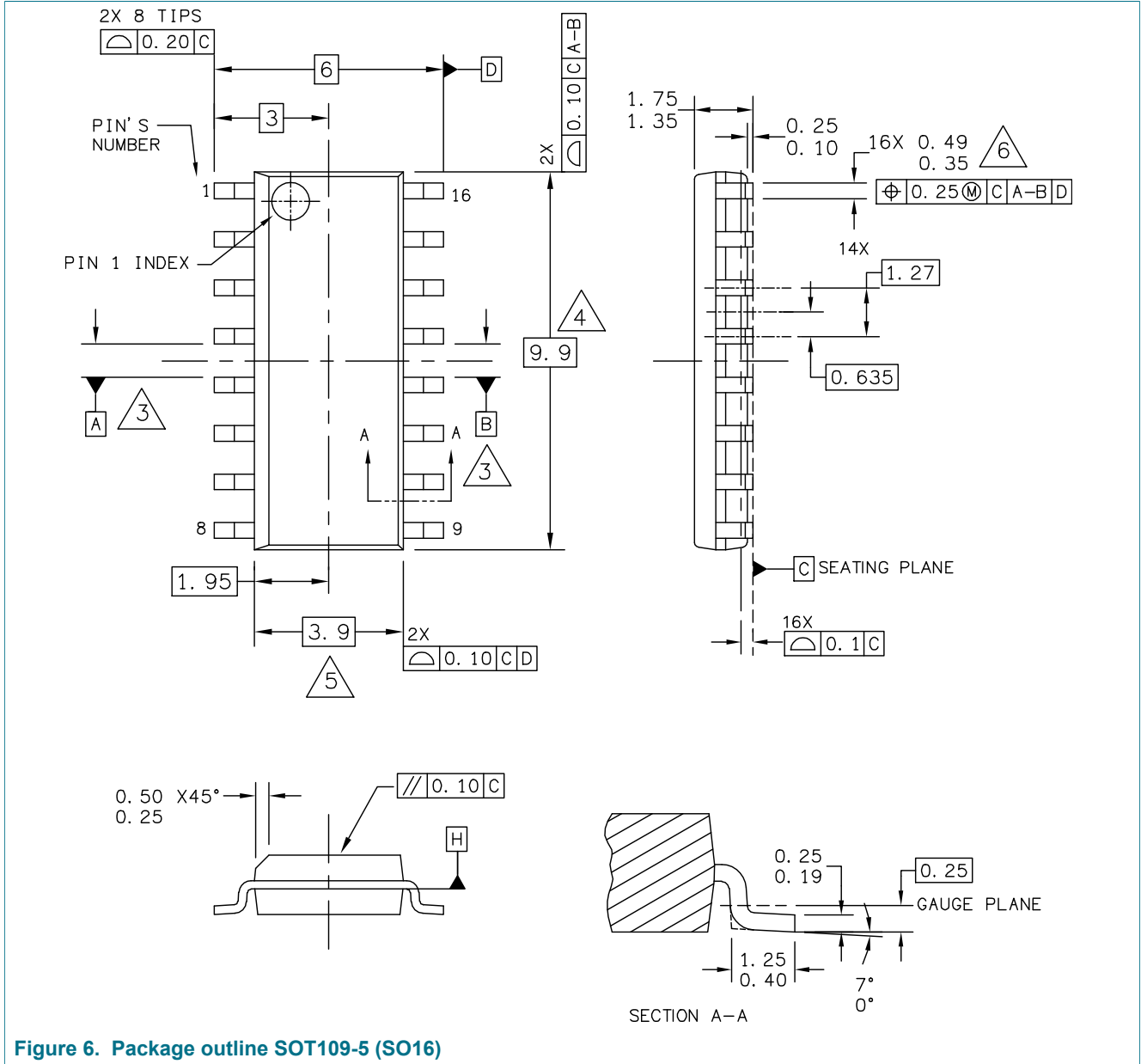


Figure 6. Package outline SOT109-5 (SO16)

11 Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
MC33664_SDS v.1.0	20180523	Technical data	—	—

12 Legal information

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